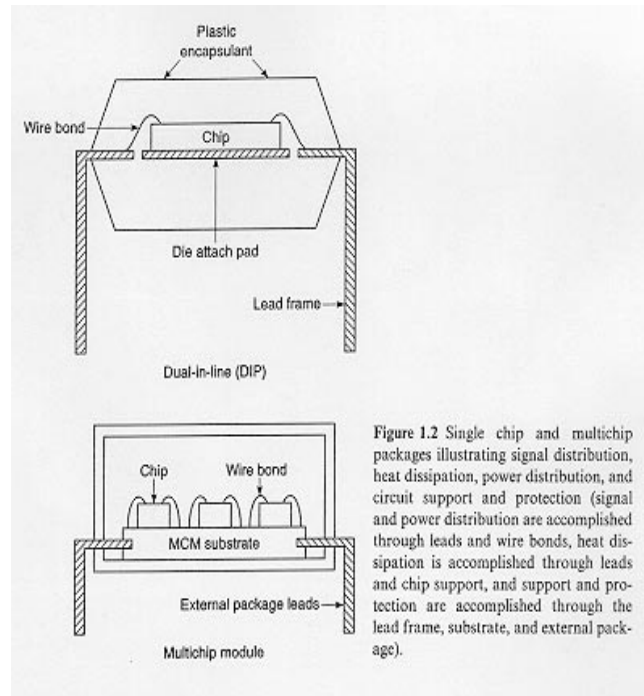


1. Course Introduction

- course deals with the fabrication of electronic packaging substrates
- electronic package = structure used to interconnect, power, cool, and protect integrated circuits (ICs) for electronic systems and products



Analogy: *IC* = brain, *Package* = body

- electronics is a \$300B world market, and packaging is a significant portion of that total which affects the following industries:
 - computing
 - telecommunications
 - aerospace
 - automotive
 - consumer electronics
- up until a few years ago, the performance of an IC was impacted little by the package;
BUT NOW: the point has been reached where advancements in IC performance are limited by packaging technology!!!
- To optimize IC performance, the package must provide:
 - improved electrical performance (i.e., less delay, low noise)
 - increase packaging density => miniaturization
 - low power consumption
 - high reliability
- fabricating a multichip module (MCM) electronic packaging substrate requires a sophisticated

sequence of dozens or hundreds of process steps, including:

- interconnect design
 - polymer deposition
 - photolithography
 - metallization
 - substrate testing
- in this course, we will go through a simple process sequence to make a 2-metal layer organic MCM substrate

2. Course Policies and Procedures (see handout)

3. Course Outline (see handout)

4. Packaging Hierarchy

- electronic systems consist of several layers of packaging, each with distinctive types of inter-connection devices:

Level 0: gate-to-gate interconnections on the chip

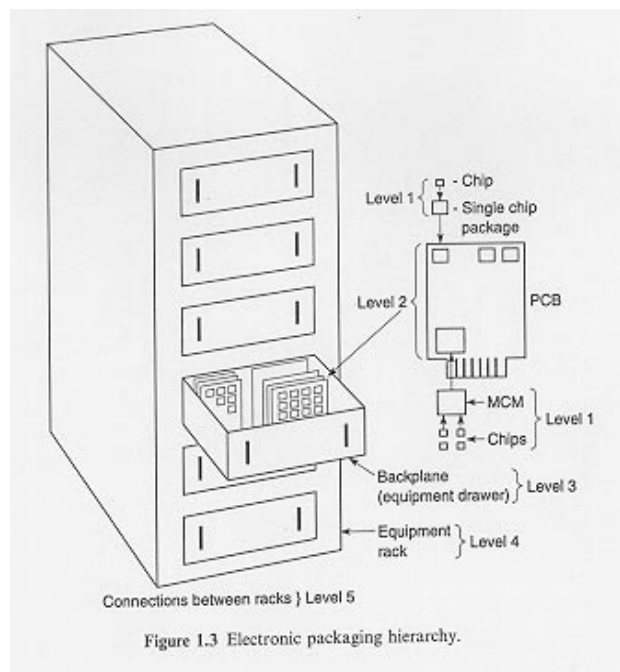
Level 1: chip-to-module connections

Level 2: board level interconnections

Level 3: board-to-board interconnections

Level 4: connections between sub-assemblies

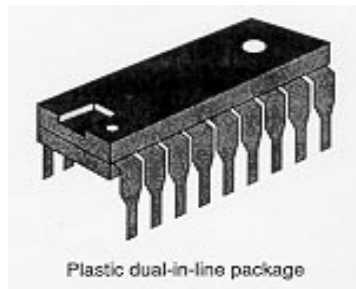
Level 5: connections between systems (i.e., computer to printer)



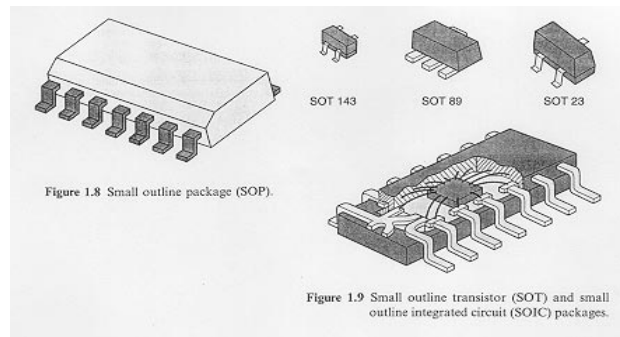
- this course concentrates on *Level 2*; the follow-on “Module Assembly” course focuses on *Level 1*

5. Evolution of Packaging Technology

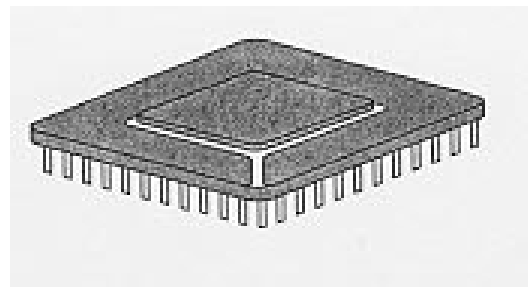
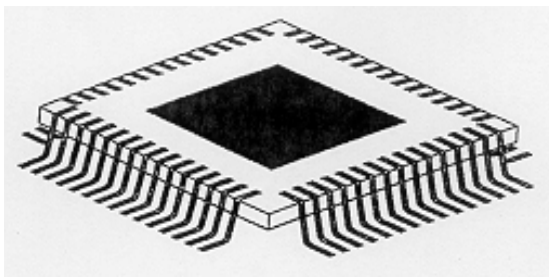
- DIP = “dual-inline-package”; what most people envision when they think of an IC “chip”
 - developed in the 1960’s
 - leads are perpendicular to the body of the package
 - ideally suited for insertion mounting onto printed wiring boards (PWBs) using plated through holes (PTH)



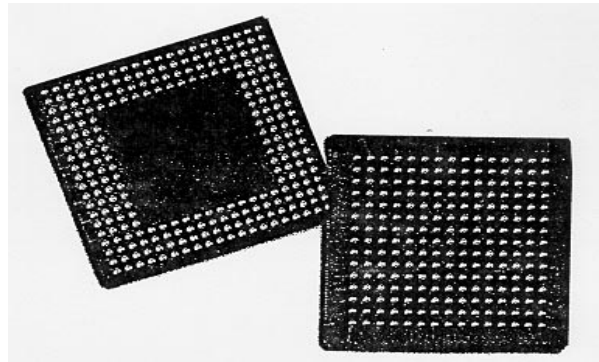
- surface mount technology (SMT)
 - developed in the 1970’s
 - leads don’t penetrate the PWB surface; ICs can be mounted on both sides => higher density
 - mounting accomplished by reflow solder technology
 - use small outline packages (SOPs), which are miniature DIPs



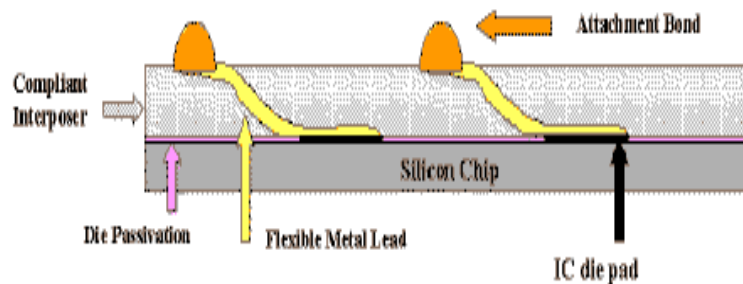
- quad flatpacks (QFPs) and pin grid arrays (PGAs)
 - developed in the 1980’s
 - leadless or leaded versions; plastic or ceramic bodies
 - have leads on all 4 sides => up to ~200 I/O’s
 - PGAs can have up to ~600 I/O’s



- ball grid arrays (BGAs)
 - developed in the early 1990's
 - replacement for QFPs
 - solder bumps in a matrix on the bottom of the package
 - higher density, smaller footprint, shorter electrical paths (i.e., *faster* signal propagation)
 - more expensive than QFP
 - natural choice for multichip module (MCM) packaging



- chip scale packages (CSPs)
 - developed in the late 1990's
 - extension of the bare IC to permit easy handling, testing, and assembly
 - about 1.2 times the size of bare die
 - offer a method for subjecting ICs to full functional and reliability testing while maintaining the approximate size and performance of a bare die
 - includes micro-ball grid array (μ BGA), mini-BGA, and μ SMT packages



- Major Motivation: pack more electronic functionality and higher speed performance into smaller volume

6. Driving Forces for Packaging Technology

- Major Issues: manufacturing cost, size and weight, signal integrity, heat dissipation, mechanical stability, testability, reliability

- *Manufacturability and Cost:*
 - includes materials, fabrication steps, and the cost of the IC
 - costs also incurred from testing, rework, yield loss
 - manufacturability depends on process control, cycle time, repairability, equipment downtime, design tolerances
- *Electrical Design:*
 - interconnect speed now plays a dominant role in determining performance limits
 - each connection has parasitic capacitance, resistance, and inductance that limit speed, potentially distort signals, and add noise
 - leads for connections are also a source of reliability problems
 - several factors need to be considered, including:
 - lead length
 - matched impedances
 - low ground resistance
 - simultaneous switching and power supply spiking
- *Thermal Design:*
 - objective = remove heat from the junctions of the ICs (to keep dopants from moving)
 - techniques = forced air, liquid cooling
 - considerations:
 - 1) how to remove heat (from the front or backside of the IC)
 - 2) air or liquid?
 - 3) thermal conductivity of the substrate
 - 4) stresses induced due to CTE mismatches
- *Mechanical Design:*
 - susceptibility to thermal stresses must be considered in design
 - tensile modulus (“stiffness”) also a consideration
- *Testability:*
 - 2 types:
 - 1) in-process testing (non-destructive)
 - 2) stress/reliability testing (destructive)
 - for MCMs, 2 phases:
 - 1) substrate (this course)
 - 2) assembled module (next course)

7. MCM Definitions and Classifications

- multichip module (MCM) = single electronic package with multiple ICs
- advantages: miniaturization, electrical and thermal performance, reliability
- Categories:
 - 1) *laminated* (MCM-L) - constructed of plastic laminate-based dielectrics and copper conductors using PWB technology; lowest cost MCMs

2) *ceramic* (MCM-C) - constructed on cofired ceramic or glass-ceramic substrates using thick film (screen printing) technologies

3) *deposited* (MCM-D)- formed by the deposition and patterning of thin films; highest performance MCMs

- comparison:

Characteristic	MCM-L	MCM-C	MCM-D
Maximum Wiring Density (cm/cm ²)	300	800	250 - 750
Minimum Line Width (μm)	60 - 100	75 - 100	8 - 25
Line Spacing (μm)	625 - 2250	125 - 450	25 - 75
Via Diameter (μm)	300 - 500	100	8 - 25
Cost (\$/cm ²)	3 - 30	50 - 1000	800 - 8000

- to optimize cost and performance trade-offs, the high performance of MCM-D at the low cost of MCM-L is desirable
- in this hybrid technology, called MCM-L/D, substrate structures are formed as multiple layers of metal separated by dielectric material
- Georgia Tech Packaging Research Center (PRC) “single-level-integrated module” (SLIM) implementation of the MCM-L/D paradigm:

